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Applicant: Hajime KOMURA et al.

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor/Applicant Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclosed	No
//DaR//	GR	0 060 944 A	09/1982	EP	Westinghouse Electric Corp.				
//DaR//	HR	03/019169 A1	03/2003	WO	Sugimura Et al.	X			
//DaR//	IR	0 902 279 A1	03/1999	EP	NGK Spark Plug Co.				
//DaR//	JR	0 731 351 A2	09/1996	EP	NGK Insulators Ltd.				
//DaR//	KR	0 903 576 A2	03/1999	EP	NGK Spark Plug Co.				
//DaR//	LR	2003-42989	02/2003	JP	Figaro Eng Inc	X			
//DaR//	MR	54-24095	02/1979	JP	Fuji Electric Co Ltd	X			
	NR								
	OR								
	PR								

OTHER INFORMATION in this order (Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

//DaR//	QR	European Search Report mailed January 10, 2008 issued in EP Application No. 05 70 3821							
//DaR//	RR	Hornillo et al., "Influence of the deposition conditions of SnO <sub>2</sub> thin films by reactive sputtering on the sensitivity of urban pollutants", Sensors and Actuators B 45 (1997) pp. 193-198							
//DaR//	SR	Skafidas et al., "Modelling and simulation of tin oxide based thick-film gas sensors using Monte Carlo techniques", Sensors and Actuators B, Vol. 819, No. 1-3, part 2, April 1994, pp. 724-728; (Abstract attached, Proceedings of the EUROSensors VII Conference, Budapest, Hungary, September 26-29, 1993)							
	TR								
	UR								
	VR								
	WR								
	XR								

Examiner /David Rogers/

Date Considered: 10/20/2008

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.